PCN Number: 20		2018	181213000.1		PCN Date:		:	Dec 17, 2018	
Title: Transfer of select (elect C	C10 devices from ANAM-1 to DMOS5 Wafer Fab site						
Customer	Contact:		PCN Manager		Dept:			Quality Services	
Proposed 1 st Ship Date:		:	Mar 17, 2019 Estima Availal		ated Sample ibility:		le	Date provided at sample request.	
Change Type:									
Assembly Site			Assembly Process				Assembly Materials		
Design			☐ Electrical Specification				Mechanical Specification		
Test S	Site		Packing/Shipping/Labeling				Test Process		
			Wafer Bump Material				Wa	Wafer Bump Process	
			☐ Wafer Fab Materials				Wafer Fab Process		
			Part number change						
PCN Details									

Description of Change:

This change notification is to announce the transfer of select devices from ANAM-1 to the DMOS5 Wafer Fab site. Fab support from ANAM-1 has been discontinued. Buffer inventory has been built to cover the notification period of this change notification.

Current (Discontinued)				New (Transfer to Location)			
Current Fab Site	Fab Process	Probe Site	Wafer Diameter	New Fab Site	Fab Process	Probe Site	Wafer Diameter
ANAM-1	C10	DBUMP	200mm	DMOS5	C10	EBT	200mm

Reason for Change:

Discontinued Fab support from ANAM-1

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
ANAM-1	ANM	KOR	Bucheon-si

New:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	DM5	USA	Dallas

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS
MADE IN: Malaysia
2DC: 2Q:
MSL '2 /260C/1 YEAR SEAL DT
MSL 1 /235C/UNLIM 03/29/04

(L)T0:3750



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812

(20L) CS0: SHD (21L) CC0:USA (22L) AS0: MLA (23L) ACO: MYS

Product Affected:

CDCVF855PW	CDCVF855PWRG4	SN65LV1224BDBR	SN65LV1224BRHBRG4
CDCVF855PWG4	SN65LV1224BDB	SN65LV1224BDBRG4	SN65LV1224BRHBT
CDCVF855PWR	SN65LV1224BDBG4	SN65LV1224BRHBR	

Qualification Report

Approve Date 24-July-2018

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

The Displayer and Hamilton of the Control of the Co							
Туре	Test Name / Condition	Duration	Qual Device: TLK1501IRCP	QBS Process Reference: TLK2500IRCP	QBS Package Reference: TLK2201BIRCP		
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0		
CDM	ESD - CDM	1000 V	1/3/0	-	-		
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-		
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-		
HBM	ESD - HBM	4000 V	1/3/0	-	-		
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-		
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0		
LU	Latch-up	(Per JESD78)	1/6/0	-	-		
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0		

- QBS: Qual By Similarity
- Qual Device TLK1501IRCP is qualified at LEVEL3-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 24-July-2018

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TLK2501IRCP	QBS Process Reference: TLK2500IRCP	QBS Package Reference: TLK2201BIRCP
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0
CDM	ESD - CDM	1000 V	1/3/0	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	4000 V	1/3/0	-	-
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0
LU	Latch-up	(Per JESD78)	1/6/0	-	-
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0

- QBS: Qual By Similarity
- Qual Device TLK2501IRCP is qualified at LEVEL3-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k hours, 140C/480 hours, 150C/300 hours, 155C/240 hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k hours, and 170C/420 hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com